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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet	1	of	2

Complete if Known	
Application Number	10/551,714
Filing Date	July 20, 2006
First Named Inventor	Yair EIN-ELI et al
Art Unit	1793
Examiner Name	PARVINI, PEGAH
Attorney Docket Number	30579

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. [1]	Document Number Number-Kind Code [2] (if known)	Publication Date DD-MMM-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	1	2002/0066234	06-Jun-2002	Cote et al.	
	2	2004/0144755	29-Jul-2004	Motonari et al.	
	3	2004/0226918	18-Nov-2004	Lee et al.	
	4	2005/0252092	17-Nov-2005	Kim et al.	
	5	4,671,851	09-Jun-1987	Beyer et al.	
	6	4,910,155	20-Mar-1990	Cote et al.	
	7	6,126,514	03-Oct-2000	Muroyama	
	8	6,383,240	07-May-2002	Nishimoto et al.	
	9	6,831,015	14-Dec-2004	Inoue et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. [1]	Foreign Patent Documents Country Code [3] Number [4] Kind Code [5] (*if known*)	Publication Date DD-MMM-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T [6]
	10	EP 1096556	02-May-2001	Brusic et al.		
	11	JP 2006-316167	24-Nov-2006	Shibata et al.		
	12	WO 2005/047410	26-May-2005	Uotani et al.		
	13	WO 98/42790	01-Oct-1998	Avanzino et al.		
	14	WO 98/42791	01-Oct-1998	Avanzino et al.		

Examiner Signature		Date Considered	

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Sheet	2	Of	2

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[2]
	15	Chan et al. "Oxide Film Formation and Oxigen Adsorption on Copper in Aqueous Media as Probed by Surface-Enhanced Raman Spectroscopy", Journal of Physical Chemistry, B, 103: 357-365, 1999.	
	16	Feng et al. "Corrosion Mechanisms and Products of Copper in Aqueous Solutions at Various pH Values", Corrosion, 53(5): 398-407, May 1997.	
	17	Hamilton et al. "In Situ Raman Spectroscopy of Anodic Films Formed on Copper and Silver in Sodium Hydroxide Solution", Journal of the Electrochemical Society, 139: 739-745, 1986.	
	18	Kunze et al. "In Situ Scanning Tunneling Microscopy Study of the Anodic Oxidation of Cu(111) in 0.1 M NaOH", Journal of Physical Chemistry B, 105: 4263-4269, 2001.	
	19	Maurice et al. "In Situ Scanning Tunneling Microscope Study of the Passivation of Cu(111)", Journal of the Electrochemical Society, 146(2): 524-530, 1999.	
	20	Maurice et al. "In Situ STM Study of the Initial Stages of Oxidation of Cu(111) in Aqueous Solution", Surface Science, 458: 185-194, 2000.	
	21	Mayer et al. "An In Situ Raman Spectroscopy Study of the Anodic Oxidation of Copper in Alkaline Media", Journal of Electrochemical Society, 139(2): 426-434, February 1992.	
	22	Melendres et al. "In-Situ Synchrotron Far Infrared Spectroscopy of Surface Films on A Copper Electrode in Aqueous Solutions", Journal of Electroanalytical Chemistry, 449: 215-218, 1998.	
	23	Steigerwald et al. "Electrochemical Potential Measurements During the Chemical-Mechanical Polishing of Copper Thin Films", Journal of the Electrochemical Society, 142(7): 2379-2385, July 1995.	
	24	Strehblow et al. "The Investigation of the Passive Behaviour of Copper in Weakly Acid and Alkaline Solutions and the Examination of the Passive Film by ESCA and ISS", Electrochimica Acta, 25: 839-850, 1980.	

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